

Notice of References Cited	Application/Control No. 10/567,347		Applicant(s)/Patent Under Reexamination KATO ET AL.	
	Examiner ADAM A. ARCIERO		Art Unit 1795	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,074,785	06-2000	Dansui et al.	429/223
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 0831542A1	03-1998	Japan	Hideo et al.	
	O	JP 10270042A	10-1998	Japan	Sei et al.	
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	IPDL PAJ JPO Machine Translation for Sei et al. (JP10-270042 A)
	V	B.D. Cullity, Elements of X-Ray Diffraction, Second Edition, Addison-Wesley Publishing Company, Inc., Massachusetts, 1978, pgs. 29, 88, 101-104, 110, 135, 136, 139-143, 151, 178, 194, 195, 199-213, 398-403
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.